

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	105	critical adj pitch	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 14:11
L3	566	capacitance adj meter	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 14:11
L4	652	capacitance adj meter	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 14:11
L5	0	2 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 14:11
L6	79	4 and (particle dust contaminant)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 14:16
L7	0	lines spaced corresponding (size or diameter)	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	OFF	2006/03/27 14:17
L8	0	wires spaced corresponding (size or diameter)	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	OFF	2006/03/27 14:17
L9	0	wires (angle pitch) corresponding (size or diameter)	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	OFF	2006/03/27 14:17
L10	1	(line wire)(angle pitch) corresponding (size or diameter)	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	ON	2006/03/27 14:19
L11	19	2 and particle	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	ON	2006/03/27 14:20
L12	496	particle monitoring semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	ON	2006/03/27 15:12

## EAST Search History

L13	0	12 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 14:20
L14	78	12 and capacitance	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 15:03
L15	1	("5247827").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 15:07
L16	0	automated and vacuum adj chamber and particle adj (detector detection monitor) and shut adj off and remote adj (control controled)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 15:09
L17	43	automated and vacuum adj chamber and particle adj (detector detection monitor)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 15:09
L18	41	12 and quality adj control	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	ON	2006/03/27 16:11
L19	1	("5440122").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 16:16
L20	0	photoliphigraphy and particl adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 16:16
L21	0	photoliphography and particl adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 16:16
L22	0	reticle and vacuum adj chamber and particl adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 16:17
L23	421807	mask vacuum adj chamber and particl adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:17
L24	0	mask and vacuum adj chamber and particl adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:17

## EAST Search History

L25	95	mask and vacuum adj chamber and particle adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:18
L26	0	photolithography and vacuum adj chamber and particle adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:18
L27	71	photo and vacuum adj chamber and particle adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:19
L28	35	reticle and vacuum same chamber and particle adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:20
L29	35	reticle and vacuum same chamber and particle adj detector and mask	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 16:21
S14	1	("20050225308").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 14:09
S16	14092	intel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 15:45
S17	6	orvek.in.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 14:35
S18	6992	particle near4 (detect detection detecting)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 14:39
S19	13	S16 and S18	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 14:39
S20	14812	particle near4 (detect detection detecting)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 14:39
S21	22	S16 and S20	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 14:40

## EAST Search History

S22	1	particle detecting (integrated circuit or ic)	US-PGPUB; USPAT; USOCR; EPO; JPO	ADJ	ON	2006/03/24 14:44
S23	510	particle detecting (integrated circuit or ic)	US-PGPUB; USPAT; USOCR; EPO; JPO	SAME	ON	2006/03/24 14:41
S24	12	particle detection circuit	US-PGPUB; USPAT; USOCR; EPO; JPO	ADJ	ON	2006/03/24 14:45
S25	1159954	particle	US-PGPUB; USPAT; USOCR; EPO; JPO	ADJ	ON	2006/03/24 14:45
S26	586	S25 and S16	US-PGPUB; USPAT; USOCR; EPO; JPO	ADJ	ON	2006/03/24 14:58
S27	22724	pair adj ((conductive adj (lines wires)) wire)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 15:00
S28	64413	(two plural pair) adj ((conductive adj (lines wires)) wire)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 15:00
S29	9709	S20 and "17"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 15:00
S30	130	S20 and S28	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:40
S31	589	particle with (monitor monitoring detection detection detecting) same vacuum	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 15:39
S32	313	S16 and (particle contaminant)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 15:45
S33	89	S16 and (particle contaminant) and vacuum	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 15:45

## EAST Search History

S34	14812	particle near4 (detect detection detecting)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:41
S35	64413	(two plural pair) adj ((conductive adj (lines wires)) wire)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:41
S36	130	S34 and S35	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:41
S37	1	S36 and reticle	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:41
S38	14092	intel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/24 18:42
S39	47	S38 and reticle and particle	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:42
S40	252	S38 and particle and (detect\$3 monitor\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:03
S41	15	S40 and reticle	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:54
S42	61	S38 and particle and (reticle pellicle)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:54
S43	21	S42 and (detect\$3 monitor\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 18:59
S44	23	S42 and (inspect\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:00
S45	286221	particle and (detect\$3 monitor\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:03

## EAST Search History

S46	82214	particle same(detect\$3 monitor\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:03
S47	4394	S46 and capacitance	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:03
S48	2838	S47 and resistance	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:05
S49	3	S48 and S38	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:04
S50	980884	S48 vacuum	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:05
S51	1233	S48 and vacuum	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:05
S52	354	S51 and (pair two plural parallel) near5 (wire line conductor)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 19:07
S53	3175044	(contamination contaminant particle) adj (detector detection monitor monitoring) (electronics circuit circuitry)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:45
S54	47	(contamination contaminant particle) adj (detector detection monitor monitoring) adj (electronics circuit circuitry)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 09:37
S55	55	(contamination contaminant particle) adj (detector detection monitor monitoring sensor sensing) adj (electronics circuit circuitry)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 09:37
S56	9	S55 and semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 09:40
S57	53	semiconductor adj processing and contamination adj (sensor monitor detector sensing monitoring detecting)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 09:44

## EAST Search History

S58	1	S57 and "438".class.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 09:44
S59	0	(438/14or438/17).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:45
S60	5682	((438/14) or (438/17)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:45
S61	295355	(contamination contaminant particle dust debris) and (detect detector detection monitor monitoring sensor sensing)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:47
S62	593	S60 and S61	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:48
S63	3	S62 and intel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:50
S64	223	particle near2 size near2 (detector monitor)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 09:52
S65	25	S64 and capacitance	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 10:16
S66	1	("4,070,660").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 10:16
S67	10	particle and switch and circuit and intel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 10:32
S68	14092	intel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2006/03/27 10:42
S69	47	S68 and reticle and particle	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:42

## EAST Search History

S70	0	S69 and any adj detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:42
S71	7	S69 and detector	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:48
S72	5182	ppd	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:48
S73	265	S72 and semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:49
S74	299838	S72 S61	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:49
S75	699	S72 and S61	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:54
S76	4	particle adj detection near2 chip	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 10:54